



STW56NM60ND

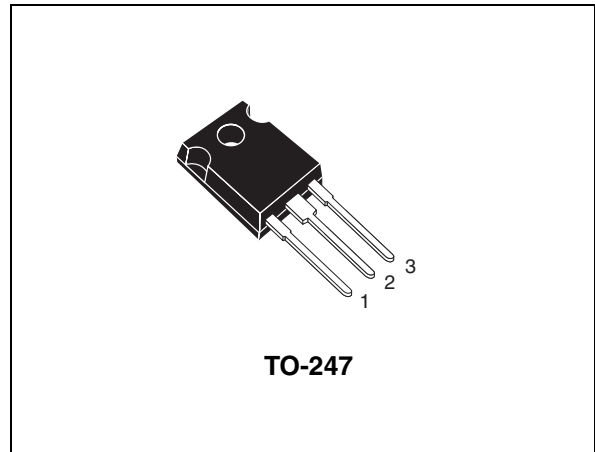
N-channel 600 V, 0.047 Ω typ., 50 A FDmesh™ II
Power MOSFET in TO-247 package

Datasheet — preliminary data

Features

| Order code | V _{DSS} @ T _{JMAX} | R _{DS(on)} max | I _D |
|-------------|-----------------------------------------|----------------------------|----------------|
| STW56NM60ND | 650 V | < 0.06 Ω | 50 A |

- The worldwide best R_{DS(on)} * area amongst the fast recovery diode devices
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance
- Extremely high dv/dt and avalanche capabilities



Applications

- Switching applications

Description

This FDmesh™ II Power MOSFET with intrinsic fast-recovery body diode is produced using the second generation of MDmesh™ technology. Utilizing a new strip-layout vertical structure, this revolutionary device features extremely low on-resistance and superior switching performance. It is ideal for bridge topologies and ZVS phase-shift converters.

Figure 1. Internal schematic diagram

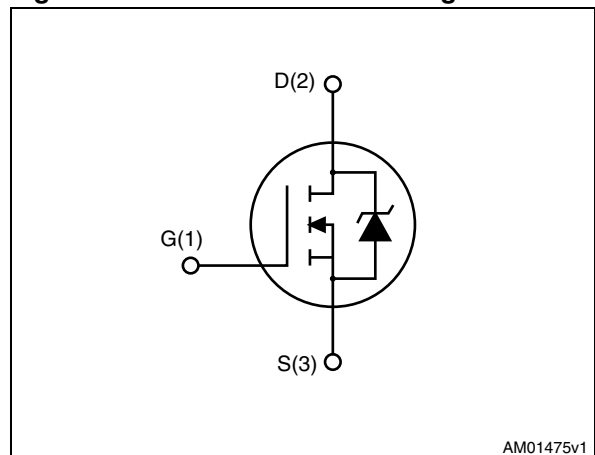


Table 1. Device summary

| Order code | Marking | Package | Packaging |
|-------------|----------|---------|-----------|
| STW56NM60ND | 56NM60ND | TO-247 | Tube |

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1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|----------------------------------------------------------------------------------------------------------------|-------------|------------------|
| V_{DS} | Drain-source voltage | 600 | V |
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$ | 50 | A |
| I_D | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 32 | A |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 200 | A |
| P_{TOT} | Total dissipation at $T_C = 25\text{ }^\circ\text{C}$ | 390 | W |
| I_{AR} | Avalanche current, repetitive or not-repetitive (pulse width limited by T_j max) | 10 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j=25\text{ }^\circ\text{C}$, $I_D=I_{AS}$, $V_{DD}=50\text{ V}$) | TBD | mJ |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 40 | V/ns |
| T_{stg} | Storage temperature | - 55 to 150 | $^\circ\text{C}$ |
| T_j | Max. operating junction temperature | 150 | $^\circ\text{C}$ |

1. Pulse width limited by safe operating area

2. $I_{SD} \leq 50\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$, $V_{DS\text{ peak}} \leq V_{(BR)DSS}$, $V_{DD} = 80\% V_{(BR)DSS}$.

Table 3. Thermal data

| Symbol | Parameter | Value | Unit |
|----------------|------------------------------------------------|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max | 0.32 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient max | 50 | $^\circ\text{C}/\text{W}$ |
| T_l | Maximum lead temperature for soldering purpose | 300 | $^\circ\text{C}$ |

2 Electrical characteristics

($T_{CASE} = 25\text{ °C}$ unless otherwise specified)

Table 4. On/off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|--------------------------------------------------|----------------------------------------------------------------------------|------|-------|-----------|--------------------------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage ($V_{GS} = 0$) | $I_D = 1\text{ mA}$, | 600 | | | V |
| I_{DSS} | Zero gate voltage drain current ($V_{GS} = 0$) | $V_{DS} = 600\text{ V}$ $V_{DS} = 600\text{ V}$, $T_C = 125\text{ °C}$ | | | 1 150 | μA μA |
| I_{GSS} | Gate-body leakage current ($V_{DS} = 0$) | $V_{GS} = \pm 25\text{ V}$ | | | ± 150 | nA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$, $I_D = 25\text{ A}$ | | 0.047 | 0.06 | Ω |

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------------|------------------------------|-----------------------------------------------------------------------------------------------|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 50\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0$ | - | 5000 | - | pF |
| C_{oss} | Output capacitance | | | 245 | | pF |
| C_{rss} | Reverse transfer capacitance | | | 10 | | pF |
| $C_{oss\ eq.}^{(1)}$ | Output capacitance | $V_{GS} = 0$, $V_{DS} = 0$ to 480 V | - | TBD | - | pF |
| R_g | Gate input resistance | $f = 1\text{ MHz}$ Gate DC Bias = 0 Test signal level = 20 mV Open drain | - | 1.7 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 200\text{ V}$, $I_D = 25\text{ A}$, $V_{GS} = 10\text{ V}$, (see Figure 3) | - | TBD | - | nC |
| Q_{gs} | Gate-source charge | | | TBD | | nC |
| Q_{gd} | Gate-drain charge | | | TBD | | nC |

1. $C_{oss\ eq.}^{(1)}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS}

Table 6. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|--------------------|--------------------------------------------------------------------------------------------------------------------------|------|------|------|------|
| $t_{d(v)}$ | Voltage delay time | $V_{DD} = 325 \text{ V}$, $I_D = 25 \text{ A}$ $R_G = 4.7 \text{ } \Omega$ $V_{GS} = 10 \text{ V}$ (see Figure 2) | - | TBD | - | ns |
| $t_{r(v)}$ | Voltage rise time | | - | TBD | - | ns |
| $t_{f(i)}$ | Current fall time | | - | TBD | - | ns |
| $t_{c(off)}$ | Crossing time | | - | TBD | - | ns |

Table 7. Source drain diode

| Symbol | Parameter | Test conditions | Min | Typ. | Max | Unit |
|-----------------|-------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------|-----|------|-----|---------------|
| I_{SD} | Source-drain current | | - | | 50 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | | | 200 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD} = 50 \text{ A}$, $V_{GS} = 0$ | - | | 1.5 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 50 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see Figure 4) | - | TBD | | ns |
| Q_{rr} | Reverse recovery charge | | | TBD | | μC |
| I_{RRM} | Reverse recovery current | | | TBD | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 50 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$ (see Figure 4) | - | TBD | | ns |
| Q_{rr} | Reverse recovery charge | | | TBD | | μC |
| I_{RRM} | Reverse recovery current | | | TBD | | A |

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

3 Test circuits

Figure 2. Switching times test circuit for resistive load

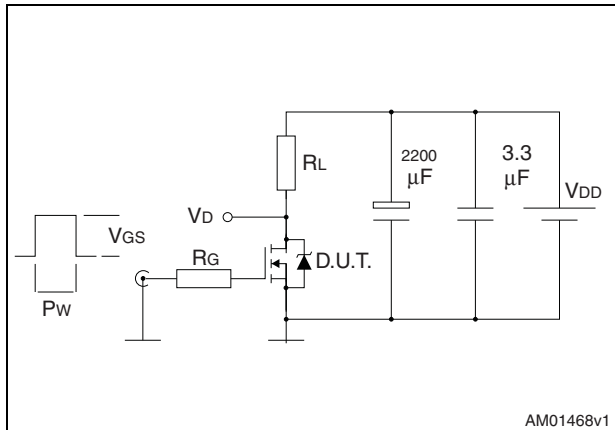


Figure 3. Gate charge test circuit

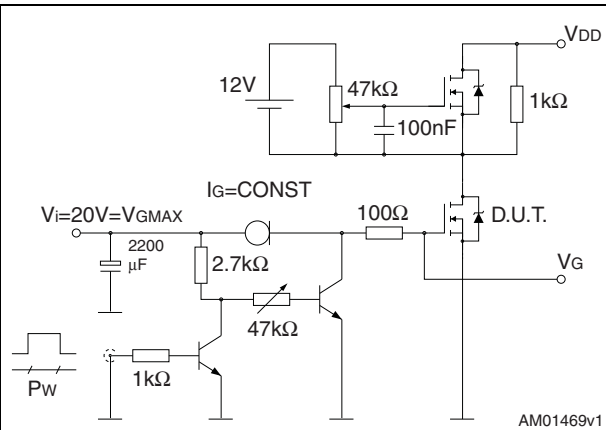


Figure 4. Test circuit for inductive load switching and diode recovery times

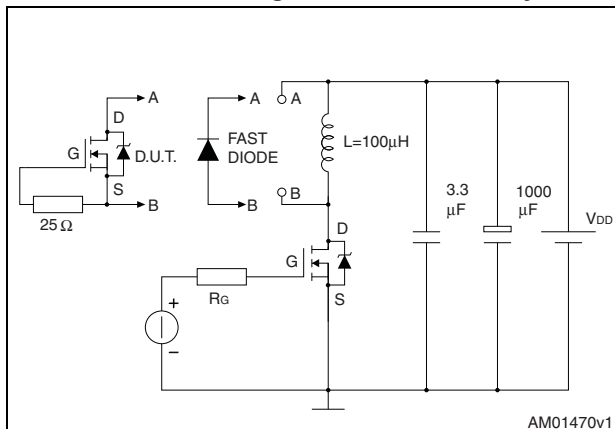


Figure 5. Unclamped inductive load test circuit

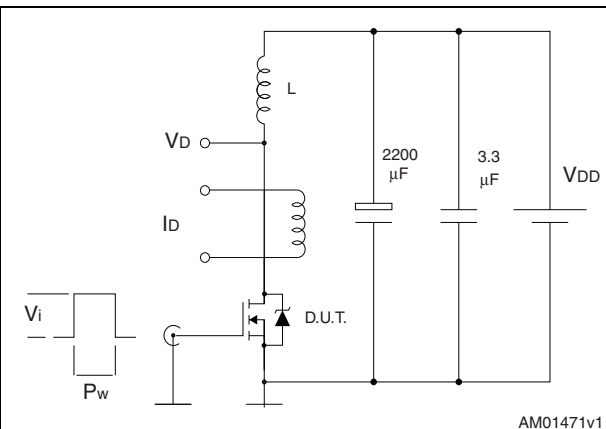


Figure 6. Unclamped inductive waveform

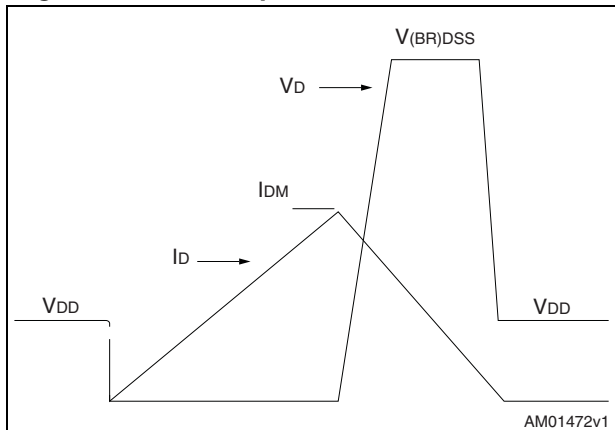
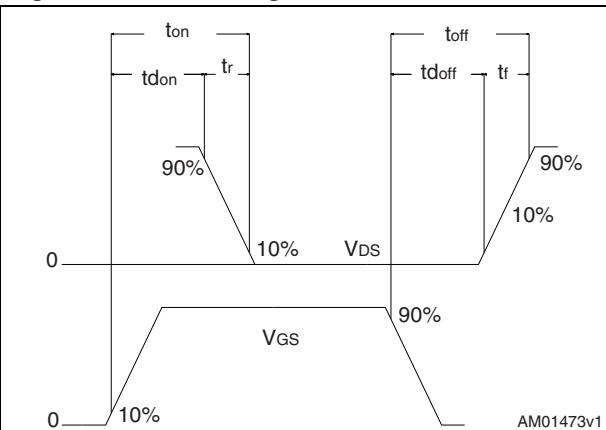


Figure 7. Switching time waveform



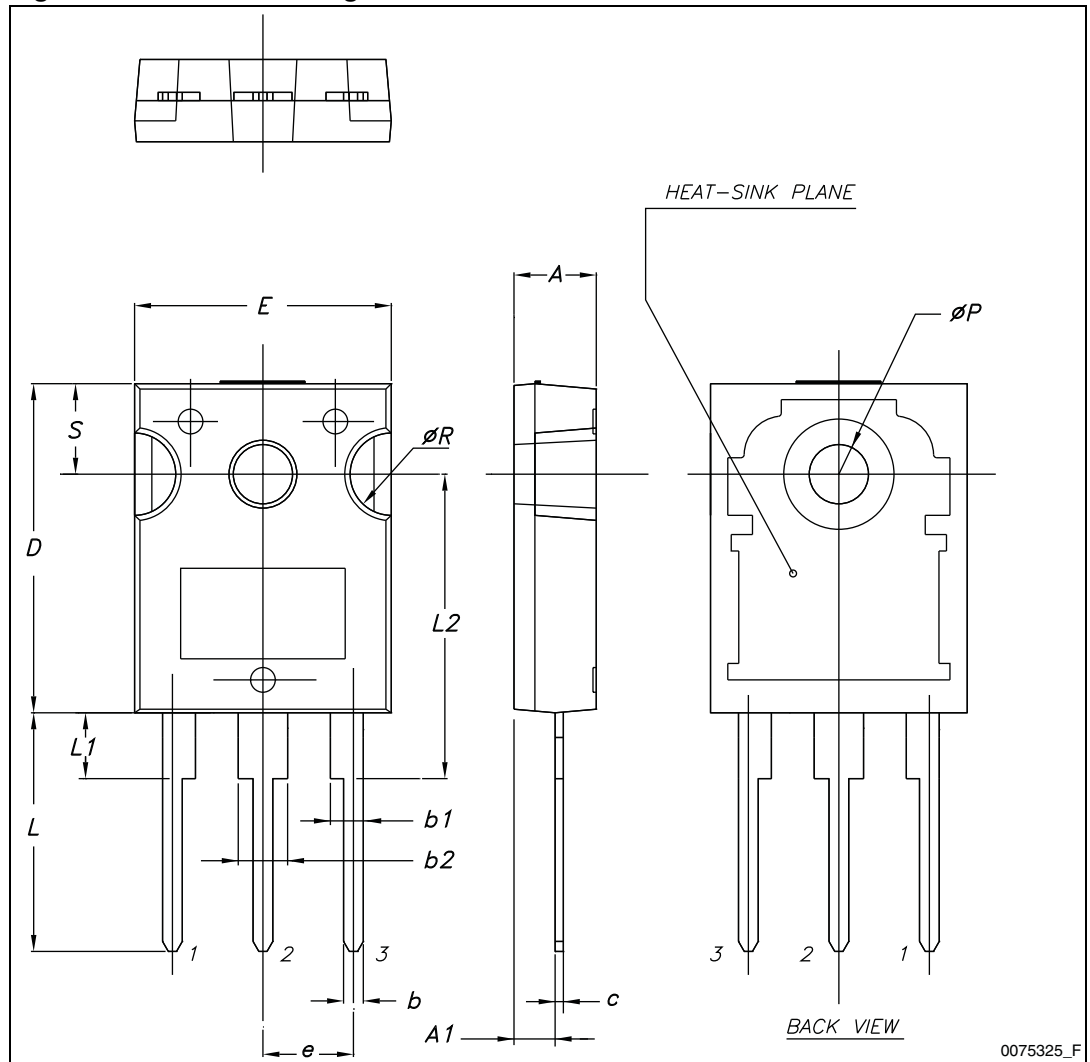
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 8. TO-247 mechanical data

| Dim. | mm | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 4.85 | | 5.15 |
| A1 | 2.20 | | 2.60 |
| b | 1.0 | | 1.40 |
| b1 | 2.0 | | 2.40 |
| b2 | 3.0 | | 3.40 |
| c | 0.40 | | 0.80 |
| D | 19.85 | | 20.15 |
| E | 15.45 | | 15.75 |
| e | | 5.45 | |
| L | 14.20 | | 14.80 |
| L1 | 3.70 | | 4.30 |
| L2 | | 18.50 | |
| ØP | 3.55 | | 3.65 |
| ØR | 4.50 | | 5.50 |
| S | | 5.50 | |

Figure 8. TO-247 drawing



0075325_F

5 Revision history

Table 9. Document revision history

| Date | Revision | Changes |
|-------------|----------|---------------|
| 13-Jul-2012 | 1 | First release |

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